

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. MI22-2236		SERIAL NO. 10/609,311		
 LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)		APPLICANT: Donald L. Yates							
		FILING DATE June 26, 2003			GROUP 2811-1754				
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*Examiner's initials		Document Number	Date	Name		Class	Subclass	Filing Date if Appropriate	
WY	AA	3,349,474	12/1963	D. H. Rauscher		438	10		
	AB	5,904,517	05/1999	Gardner et al.		438	197		
	AC	5,998,264	12/1999	Wu		438	260		
	AD	6,180,465 B1	01/2001	Gardner et al.		438	291		
	AE	6,207,485 B1	03/2001	Gardner et al.		438	216		
WY	AF	6,548,854 B1	04/2003	Kizilyalli et al.		257	310		
	AG								
WY	AH	2003/0045060 A1	03/2003	Ahn et al.		438	287		
WY	AI	2003/0045078 A1	03/2003	Ahn et al.		438	585		
FOREIGN PATENT DOCUMENTS									
		Document Number	Date	Country		Class	Subclass	Translation	
WY	AA	EP 0 851 473 A2	01/1998	EPO				Yes	No
	AK								
	AL								
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)									
WY	AM		Chang et al., Silicon surface treatments in advanced MOS gate processing, Microelectronic Engineering, (2004), pages 130-135						
WY	AM		Lemberger et al., Electrical characterization and reliability aspects of zirconium silicate films obtained from novel MOCVD precursors, Microelectronic Engineering (2004), pages 315-320						
WY	AO		Lu et al., Effects of the TaN _x interface layer on doped tantalum oxide high-k films, VACUUM (2004), pages 1-9						
EXAMINER WY		DATE CONSIDERED	4/27/05						
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W3	AM		Robertson et al., Atomic structure, band offsets, growth and defects at high-K oxide:Si interfaces, Microelectronic Engineering (2004) pages 112-120						
W3	AN		Singh et al., High and Low Dielectric Constant Materials, The Electrochemical Society <i>Interface</i> , Summer 1999, pages 26-30						
	AO								
EXAMINER <i>W3</i>		DATE CONSIDERED		4/27/05					
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<i>nm</i>	AA	4,086,074	04/78	Minot et al.	<i>438</i>	<i>61</i>	
<i>nm</i>	AB	4,622,735	11/86	Shibata	<i>438</i>	<i>303</i>	
<i>nm</i>	AC	4,683,645	08/87	Naguib et al.	<i>438</i>	<i>530</i>	
<i>nm</i>	AD	4,693,910	09/87	Nakajima et al.	<i>257</i>	<i>647</i>	
<i>nm</i>	AE	4,766,090	08/88	Coquin et al.	<i>438</i>	<i>222</i>	
<i>nm</i>	AF	5,099,304	03/92	Takemura et al.	<i>427</i>	<i>168</i>	
<i>nm</i>	AG	5,236,865	08/93	Sandhu et al.	<i>438</i>	<i>297</i>	
<i>nm</i>	AH	5,444,024	08/95	Anjum et al.	<i>438</i>	<i>143</i>	
<i>nm</i>	AI	5,470,784	11/95	Anjum et al.	<i>45</i>	<i>31</i>	
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<i>nm</i>	AM	ABSTRACT: Basceri et al., Atomic Layer Deposition for Nanoscale Cu Metalization, 10 pages (pre-April 2004).					
<i>nm</i>	AN	En et al., Plasma immersion ion implantation reactor design considerations for oxide charging, 85 SURFACE AND COATINGS TECHNOLOGY 64-69 (1996).					
<i>nm</i>	AO	Ku et al., The Application of Ion Beam Mixing, Doped Silicide, and Rapid Thermal Processing of Self-Aligned Silicide Technology, 137 J. Electrochem. Soc. No. 2, pp. 728-740 (February 1990).					
EXAMINER <i>Donald L. Yates</i>		DATE CONSIDERED <i>4/27/05</i>					
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<p style="text-align: right;"><i>2/30/04</i></p> <p>LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)</p>		APPLICANT: Donald L. Yates							
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<i>WY</i>	AA	5,670,298	09/97	Hur		<i>430</i>	<i>318</i>		
	AB	6,037,239	03/00	Jennings		<i>438</i>	<i>430</i>		
	AC	6,096,621	08/00	Jennings		<i>438</i>	<i>404</i>		
	AD	6,130,140	10/00	Gonzalez		<i>438</i>	<i>430</i>		
	AE	6,133,105	10/00	Chen et al.		<i>438</i>	<i>296</i>		
	AF	6,133,116	10/00	Kim et al.		<i>438</i>	<i>430</i>		
	AG	6,156,674	12/00	Li et al.		<i>438</i>	<i>780</i>		
<i>WY</i>	AH	6,177,235 B1	01/01	Francou et al.		<i>430</i>	<i>313</i>		
<i>WY</i>	AI	6,281,100 B1	08/01	Yin et al.		<i>438</i>	<i>585</i>		
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<i>WY</i>	AM		ABSTRACT: How to Eliminate Voiding in Porous-Low-k Dielectrics and The Mechanism of Void Formation; Lin et al.; 4 pages						
<i>WY</i>	AN		COB Stack DRAM Cell Technology beyond 100 nm Technology Node; Yongjik Park & Kinam Kim; pp. 349.1 - 349.3;						
<i>WY</i>	AO		Rubin et al., Shallow-Junction Diode Formation by implantation of Arsenic and Boron Through Titanium-Silicide Films and ..., 17 IEEE Transactions on Electron Devices, No. 1, pp. 183-190 (January 1990).						
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nk	AA	6,277,709 B1	08/01	Wang et al.	438	430	
	AB	6,277,728 B1	08/01	Ahn et al.	438	619	
	AC	6,291,363 B1	09/01	Yin et al.	438	769	
	AD	6,380,611 B1	04/02	Yin et al.	257	649	
	AE	6,383,723 B1	05/02	Iyer et al.	430	327	
	AF	6,440,793 B1	08/02	Divakaruni et al.	438	243	
	AG	6,465,325 B2	10/02	Ridley et al.	438	428	
✓	AH	6,720,638 B2	04/04	Tran	257	499	
nk	AI	6,780,728	08/04	Tran	438	243	

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<i>nm</i>	AA	2001/0006759 A1	07/01	Shipley, Jr. et al.	430	280.1	
	AB	2002/0076879 A1	06/02	Lee et al.	438	241	
	AC	2002/0196651 A1	12/02	Weis	365	100	
<i>nm</i>	AD	2003/0013272 A1	01/03	Hong et al.	438	437	
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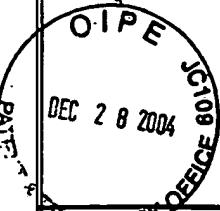
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<i>WY</i>	AA	10/655,997		Daley			09/03	
<i>WY</i>	AB	10/689,958		Basceri			10/03	
<i>WY</i>	AC	10/690,029		Derderian et al.			10/03	
<i>WY</i>	AD	10/882,118		Sandhu et al.			04/04	
<i>WY</i>	AE	10/879,367		Blalock et al.			06/04	
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